

## **ECE 3213 – Solid State Electronics**

Textbook: Ben G. Streetman, Sanjay K. Banerjee, *Solid State Electronic Devices, 6<sup>th</sup> Ed.*, Prentice-Hall, Upper Saddle River, New Jersey, 2006, ISBN 0-13-149726-X.

- I. Crystal properties
- II. Introduction to quantum mechanics
  - A. Photoelectric effect
  - B. Bohr's model
  - C. Matter as waves; wave function
  - D. Uncertainty principle
  - E. Schrodinger wave equation
  - F. Potential wells, tunneling
  - G. Hydrogen atom
  - H. Many-electron atoms
- III. Energy bands and charge carriers in semiconductors (4 contact hours)
  - A. Energy-band structure of solids; metals, dielectrics, semiconductors
  - B. Electrons and holes; effective mass
  - C. Bonds in solids; intrinsic semiconductor
  - D. Doping; extrinsic semiconductors
- IV. Statistical mechanics
  - A. Distribution function; the Fermi level
  - B. Electrons and holes at equilibrium
  - C. Temperature dependence of carrier concentrations
  - D. Compensation and space charge neutrality
- V. Physics of charge transport
  - A. Carrier drift
  - B. Carrier diffusion
- VI. Excess carriers in semiconductors
  - A. Generation and recombination
  - B. Minority carrier lifetime
  - C. Diffusion length
  - D. Continuity equation
  - E. Steady state carrier injection
- VII. P-N junctions
  - A. P-N junction contact potential
  - B. P-N junction under applied bias
  - C. Space-charge region; junction capacitance
  - D. Reverse-bias
  - E. Electric breakdown
- VIII. Metal-semiconductor junctions
  - A. Schottky barriers
  - B. Ohmic contacts

IX. Metal-oxide-semiconductor contact

- A. The ideal MOS capacitor
- B. Real MOS capacitor
- C. MOS capacitance-voltage analysis

X. Introduction to transistors

- A. Bipolar junction transistor
- B. Metal-oxide-semiconductor field-effect transistor